

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number					
		PMEG2015EA					
		Part Description					
		Nexperia DHAM	Schottky				
Assembly reliability labs		SMD package					
Based on AEC-Q101 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113					
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	810	58300	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A					
	High Temperature Reverse	Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage <sup>[1]</sup>	1000 hours	116	9280	0	
	тс	JESD22-A104					
# 44	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 eveles	170	12600	0	
# A4	remperature cycling	• '	1000 cycles	170	13600	U	
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %					
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	170	13600	0	
AS all	Autociave	11e33dre = 203 ki d (23.7 p3id)	96 Hours	170	13600	U	
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt		rated reverse voltage <sup>[1], [2]</sup>	1000 hours	170	13600	0	
# AZ dil	Temperature Reverse Blas		1000 110015	170	13000	U	
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta T_i$ =					
# A5	Intermittent Operating Life		1000 hours	170	13600	0	
+ A3	Intermittent Operating Life	100 0 101 15000 070105	1000 Hours	170	13000	U	
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	130	3900	0	
	SD		10.3	130	3300		

<sup>[1]</sup> The physical limitations of Schottky diodes have to be considered (thermal runaway).

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Schottky	9280	0	0.46	2.19E+09

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<sup>[2]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.